

FORM PTO 1449 (modified)  U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE  LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)			ATTY DOCKET NO. <b>00684.001674.5</b>		APPLICATION NO. <b>10/629,636</b> Div. of 09/695,925			
			APPLICANT		<b>Masaaki Suzuki</b>			
			FILING DATE <b>Herewith</b>			GROUP		<b>1746</b>
			U.S. PATENT DOCUMENTS					
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
<i>fly</i>		4,341,592	7/27/82	Shortes et al.	134	2		
		5,198,634	3/30/93	Mattson et al.	219	121		
		5,747,387	5/5/98	Koizumi et al.	438	708		
		5,078,832	1/7/92	Tanaka	134	1		
		5,372,651	12/13/94	Kodama	134	26		
		5,094,898	3/10/92	Morita et al.	428	64		
		5,215,592	6/1/93	Jackson	134	1		
		4,028,135	6/7/77	Vig et al.	134	1		
		5,068,040	11/26/91	Jackson	210	748		
		4,715,392	12/29/87	Abe et al.	134	62		
		5,158,100	10/27/92	Tanaka et al.	134	105		
<i>AC</i>		5,150,239	9/22/92	Watanabe et al.	359	80		
FOREIGN PATENT DOCUMENTS								
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO OR ABSTRACT	
<i>AC</i>		02-000315	1/5/90	Japan			abstract	
<i>AC</i>		63-271938	11/9/88	Japan			yes	
OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)								
<i>fly</i>		K.A. Valiev, et al., "Interactions of Short-Wave UV Radiation on Thin Layers of Organic Compounds", Mickroelectronika, vol. 17, no. 6, pp. 522-527 (1988) with abstract.						
		J.R. Vig., "UV/Ozone Cleaning of Surfaces", J. Vac. Sci. Technol., vol. A3, no. 3, Part 1, pp. 1027-1034 (1985).						
		McGraw-Hill Encyclopedia of Physics, S.P. Parker, ed., p. 1135 (1983).						
<i>Reff</i>		L. Zafonte, et al., "UV/Ozone Cleaning for Organics Removal on Silicon Wafers", SPIE vol. 470 Optical Microlithography III: Technology for the Next Decade, pp. 164-175 (1984).						
EXAMINER	<i>A M ARNOFF</i>			DATE CONSIDERED	<i>9/17/09</i>			

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. Sheet 1 of 2

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